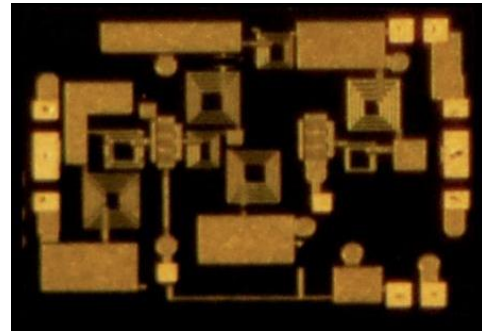


### Applications

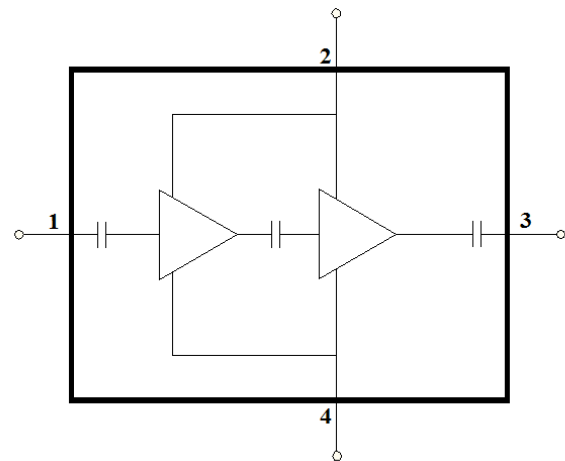
- Commercial and Military Radar
- Satellite Communications



### Product Features

- Frequency Range: 2–6GHz
- NF: 1.5dB
- OTOI: 32dBm
- Small Signal Gain: 25dB
- Return Loss: >10dB
- P1dB: 22dBm
- Bias:  $V_D = 10V$ ,  $I_{DQ} = 110mA$ ,  $V_G = -2.3V$  Typical
- Chip Dimensions: 2.1 x 1.5 x 0.10mm

### Functional Block Diagram



### General Description

TriQuint's TGA2611 is a broadband Low Noise Amplifier fabricated on TriQuint's production 0.25um GaN on SiC process (TQGaN25). Covering 2–6GHz, the TGA2611 typically provides 22dBm P1dB, 25dB of small signal gain, 1.5dB of noise figure and 32dBm of OTOI. In addition to the high overall electrical performance, this GaN amplifier also provides a high level of input power robustness. Able to survive up to 2W of input power without performance degradation, TriQuint's TGA2611 provides flexibility regarding receive chain protection never before seen with GaAs technology.

Fully matched to 50 ohms with integrated DC blocking caps on both I/O ports, the TGA2611 is ideally suited for radar and satellite communications.

Lead-free and RoHS compliant  
Evaluation Boards are available upon request.

### Pad Configuration

| Pad No. | Symbol |
|---------|--------|
| 1       | RF In  |
| 2       | $V_D$  |
| 3       | RF Out |
| 4       | $V_G$  |

### Ordering Information

| Part    | ECCN  | Description       |
|---------|-------|-------------------|
| TGA2611 | EAR99 | 2 – 6 GHz GaN LNA |

### Absolute Maximum Ratings

| Parameter                                   | Value        |
|---------------------------------------------|--------------|
| Drain Voltage ( $V_D$ )                     | 40V          |
| Gate Voltage Range ( $V_G$ )                | -5 to 0V     |
| Drain Current ( $I_D$ )                     | 200mA        |
| Gate Current ( $I_G$ )                      | -1 to 4.2mA  |
| Power Dissipation, 85 °C ( $P_{DISS}$ )     | 6W           |
| Input Power, CW, 50 $\Omega$ , ( $P_{IN}$ ) | 33dBm        |
| Channel temperature ( $T_{CH}$ )            | 275°C        |
| Mounting Temperature (30 Seconds)           | 320°C        |
| Storage Temperature                         | -55 to 150°C |

Operation of this device outside the parameter ranges given above may cause permanent damage. These are stress ratings only, and functional operation of the device at these conditions is not implied.

### Recommended Operating Conditions

| Parameter                  | Value         |
|----------------------------|---------------|
| Drain Voltage ( $V_D$ )    | 10V           |
| Drain Current ( $I_{DQ}$ ) | 110mA         |
| Gate Voltage ( $V_G$ )     | -2.3V Typical |

Electrical specifications are measured at specified test conditions. Specifications are not guaranteed overall operating conditions.

### Electrical Specifications

Test conditions unless otherwise noted: 25 °C,  $V_D$  = 10V,  $I_{DQ}$  = 110mA,  $V_G$  = -2.3V Typical

| Parameter                             | Min | Typical | Max | Units |
|---------------------------------------|-----|---------|-----|-------|
| Operational Frequency Range           | 2.0 |         | 6.0 | GHz   |
| Small Signal Gain                     |     | 25      |     | dB    |
| Input Return Loss                     |     | >10     |     | dB    |
| Output Return Loss                    |     | >10     |     | dB    |
| Noise Figure                          |     | 1.5     |     | dB    |
| Output Power at 1 dB Gain Compression |     | 22      |     | dBm   |
| Output TOI                            |     | 32      |     | dBm   |
| Gain Temperature Coefficient          |     | -0.03   |     | dB/°C |
| Noise Figure Temperature Coefficient  |     | 0.007   |     | dB/°C |

### Thermal and Reliability Information

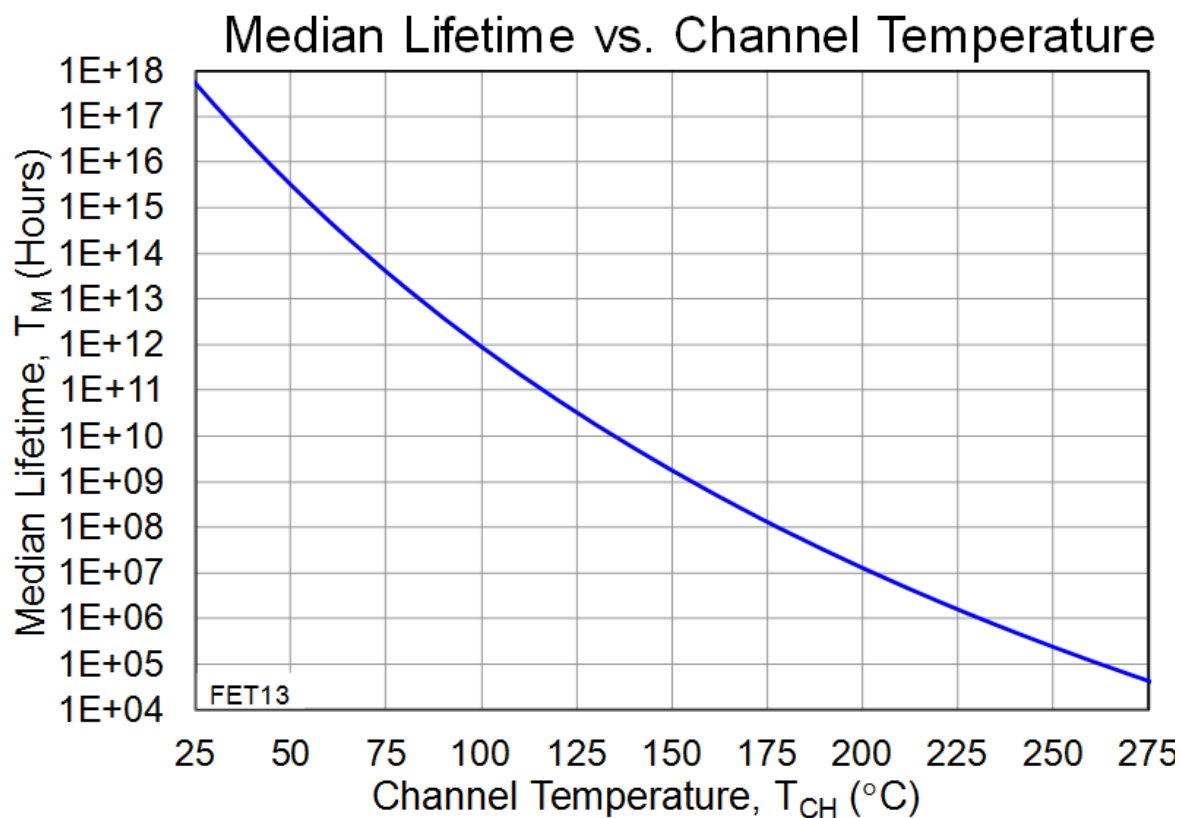
| Parameter                                           | Test Conditions                                                                   | Value                 | Units        |
|-----------------------------------------------------|-----------------------------------------------------------------------------------|-----------------------|--------------|
| Thermal Resistance ( $\theta_{JC}$ ) <sup>(1)</sup> | $V_D = 10V$ , $I_{DQ} = 110mA$ , $P_{DISS} = 1.1W$ , $T_{baseplate} = 85^\circ C$ | 18.6                  | $^\circ C/W$ |
| Channel Temperature ( $T_{CH}$ )                    |                                                                                   | 105                   | $^\circ C$   |
| Median Lifetime ( $T_M$ )                           |                                                                                   | $4.52 \times 10^{11}$ | Hrs          |

Notes:

1. Thermal resistance measured to back of carrier plate. MMIC mounted on 40 mils CuMo carrier using 1.5 mil 80/20 AuSn.

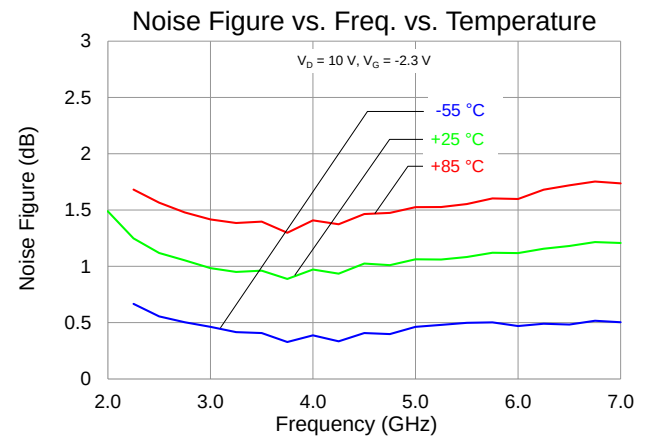
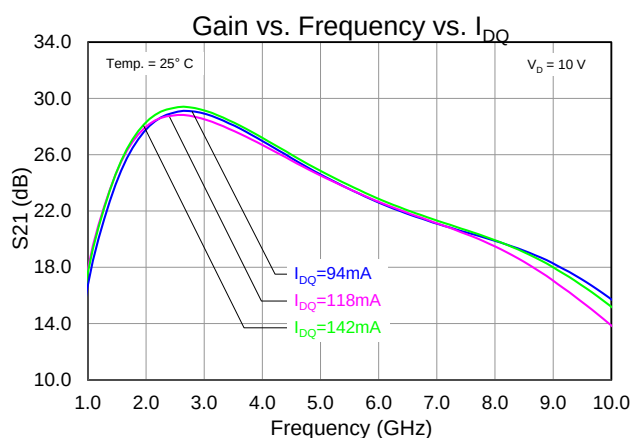
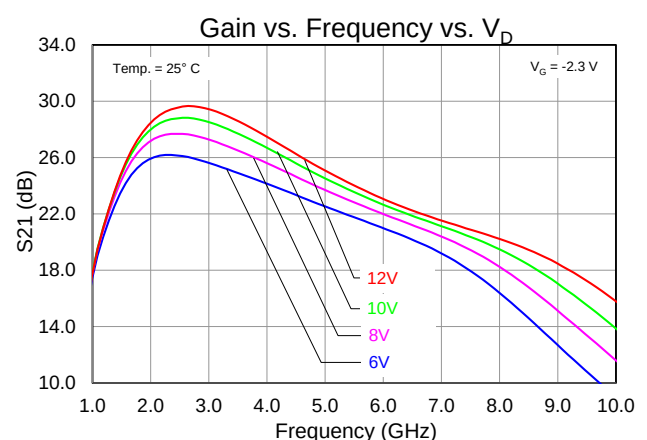
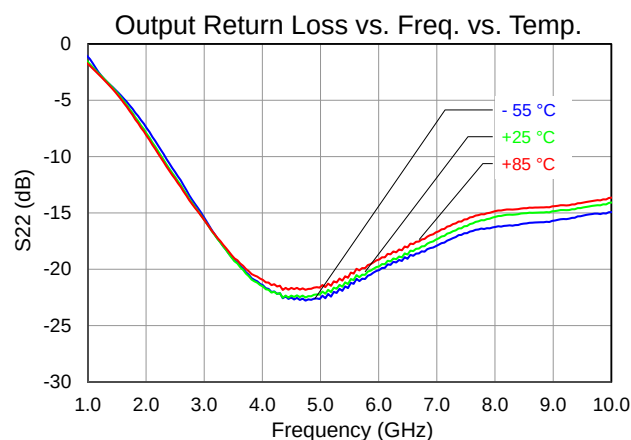
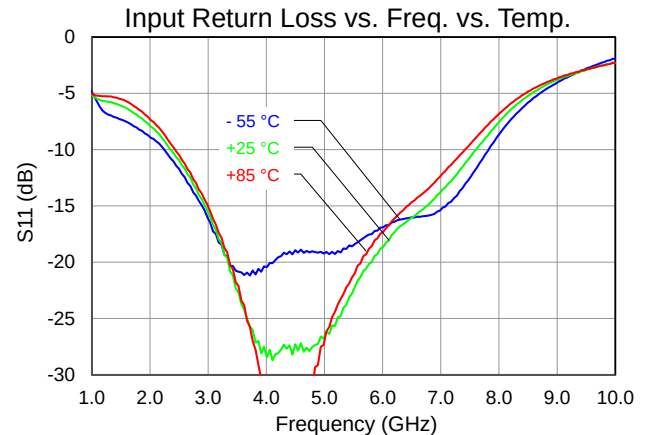
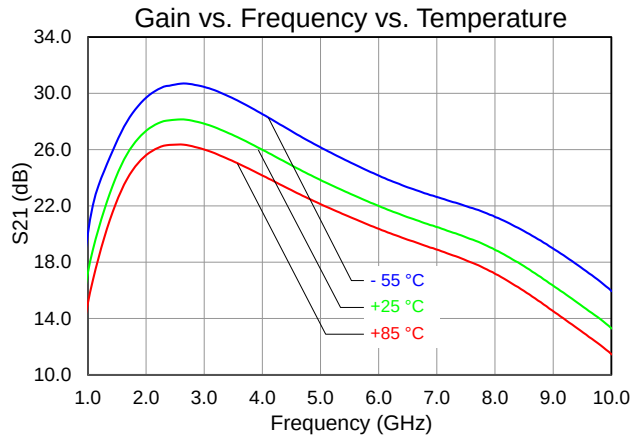
### Median Lifetime

Test Conditions:  $V_D = 40V$ ; Failure Criteria is 10% reduction in  $I_{D\_MAX}$



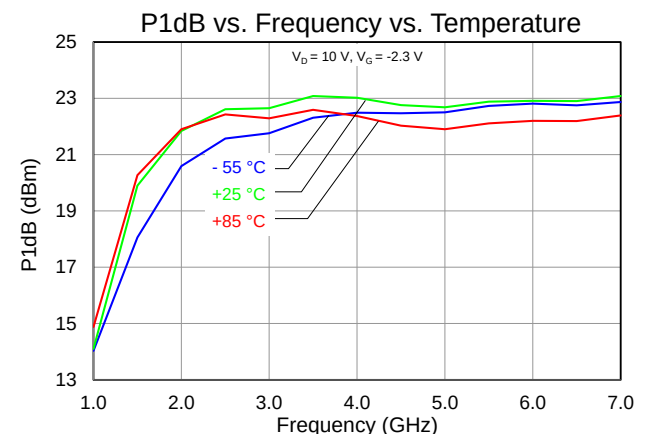
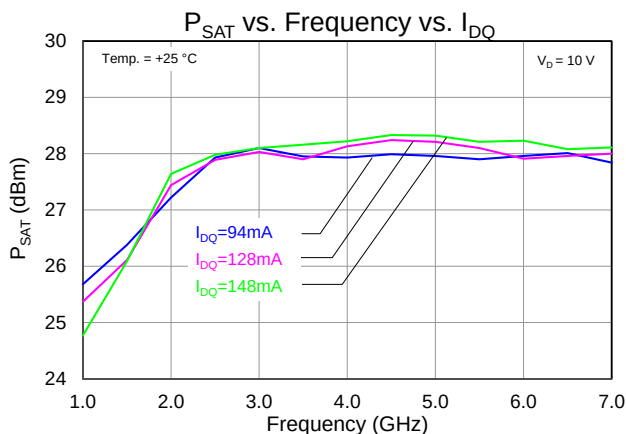
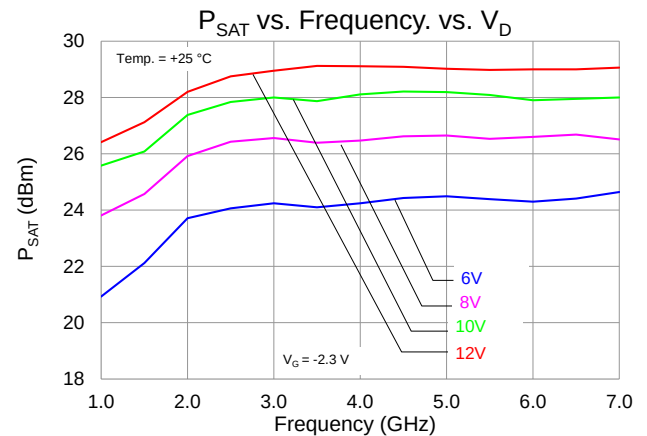
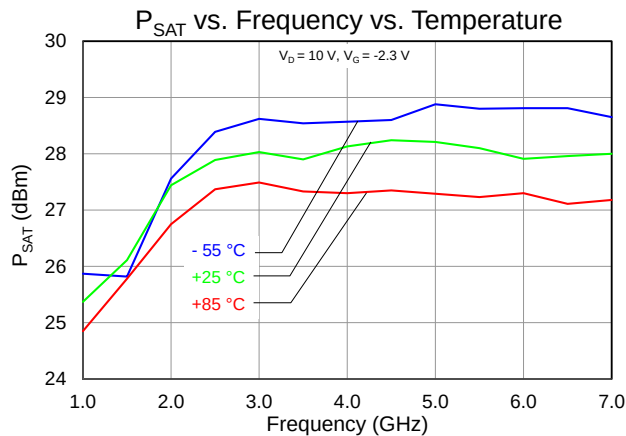
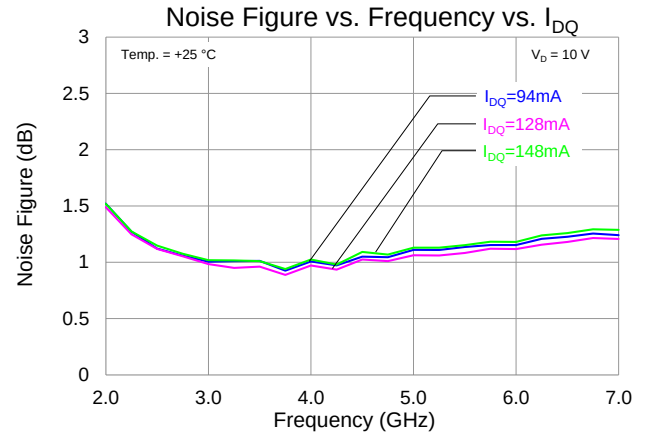
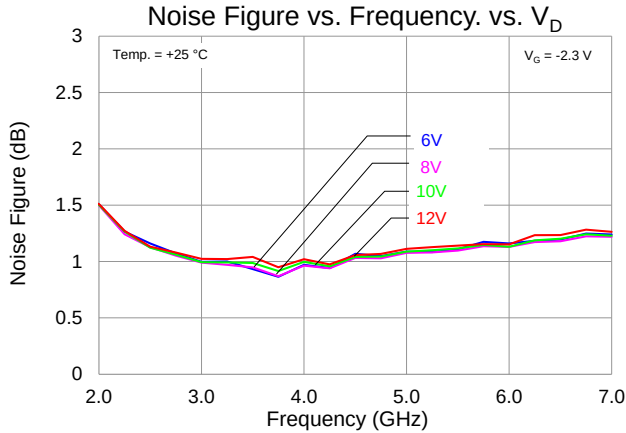
## Typical Performance

Conditions unless otherwise specified:  $V_D = 10V$ ,  $I_{DQ} = 110mA$ ,  $V_G = -2.3V$  Typical



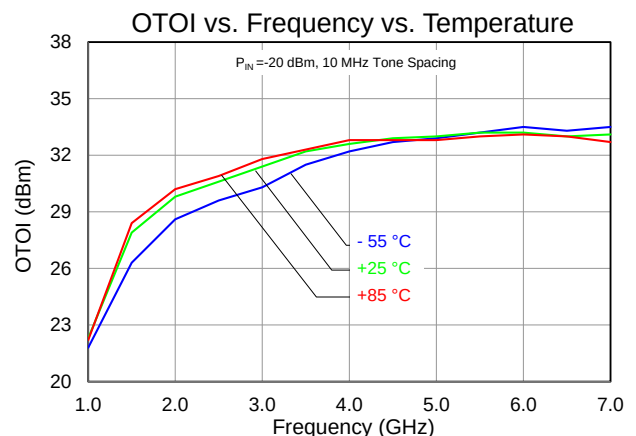
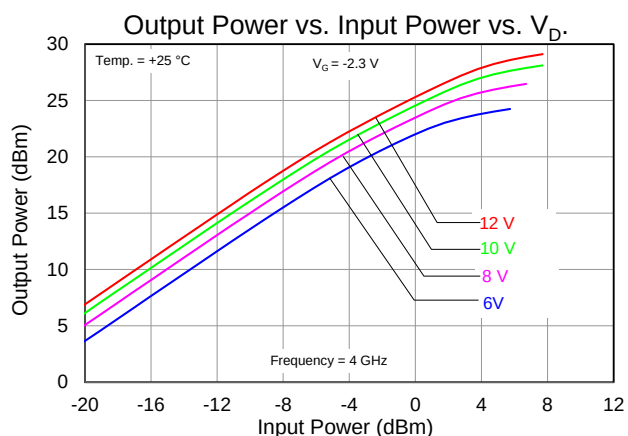
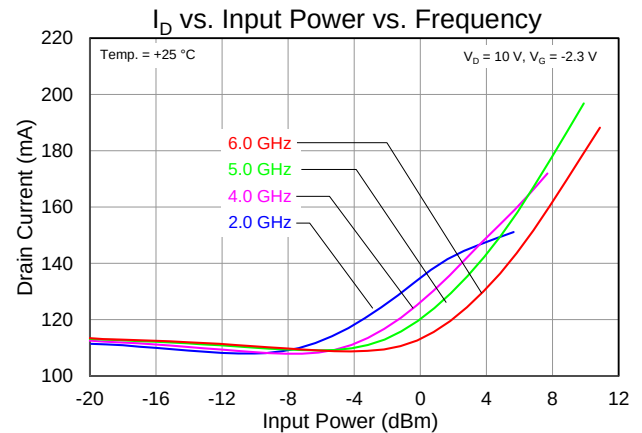
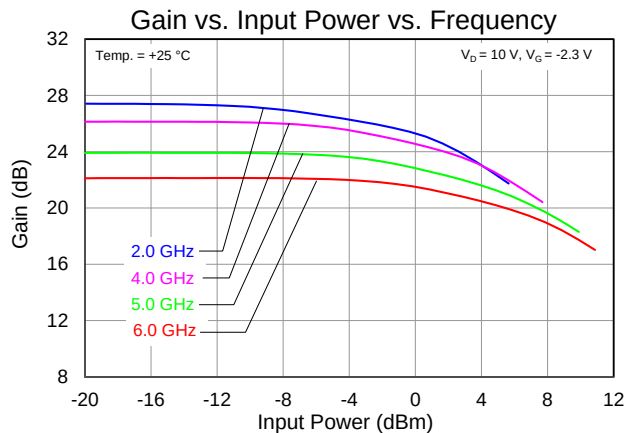
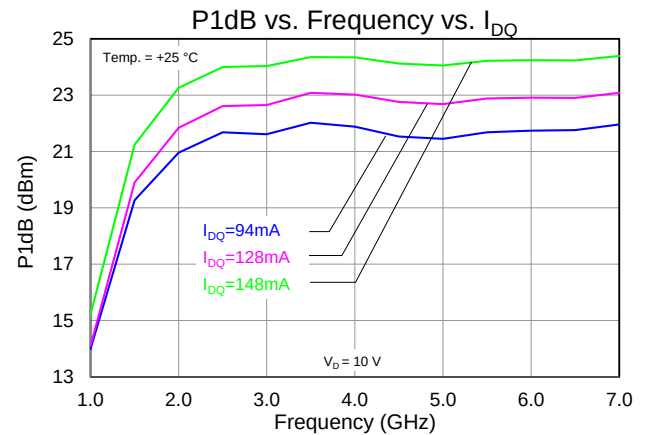
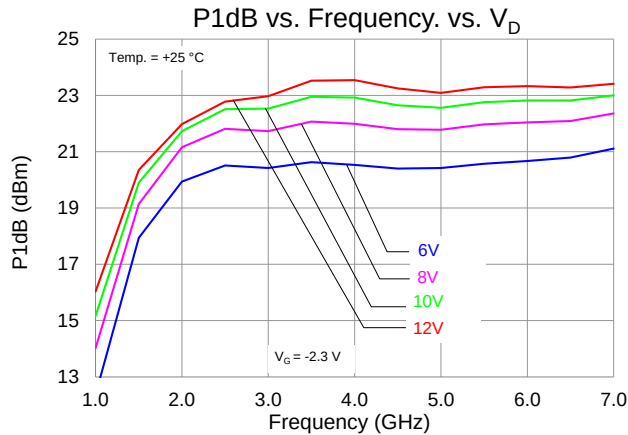
## Typical Performance

Conditions unless otherwise specified:  $V_D = 10V$ ,  $I_{DQ} = 110mA$ ,  $V_G = -2.3V$  Typical



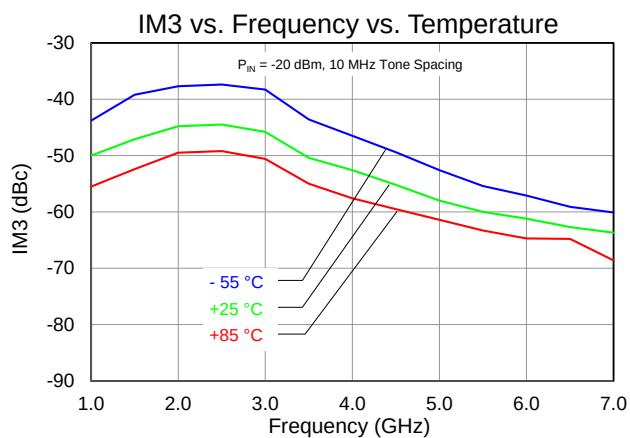
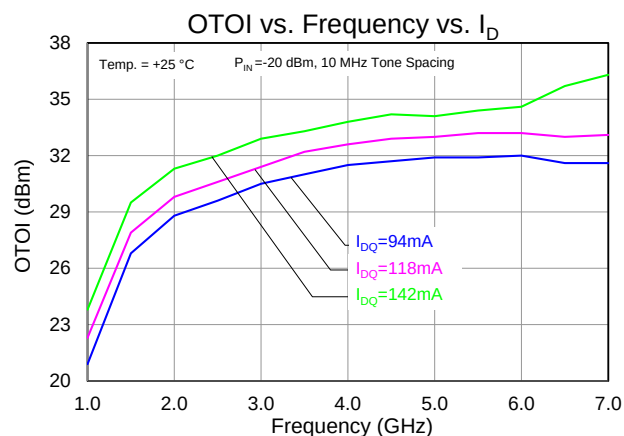
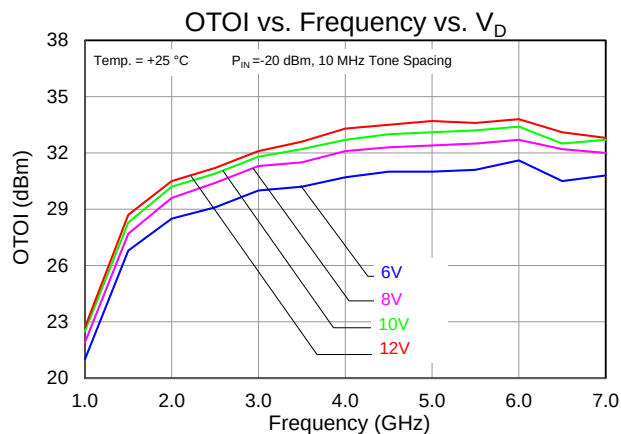
## Typical Performance

Conditions unless otherwise specified:  $V_D = 10V$ ,  $I_{DQ} = 110mA$ ,  $V_G = -2.3V$  Typical

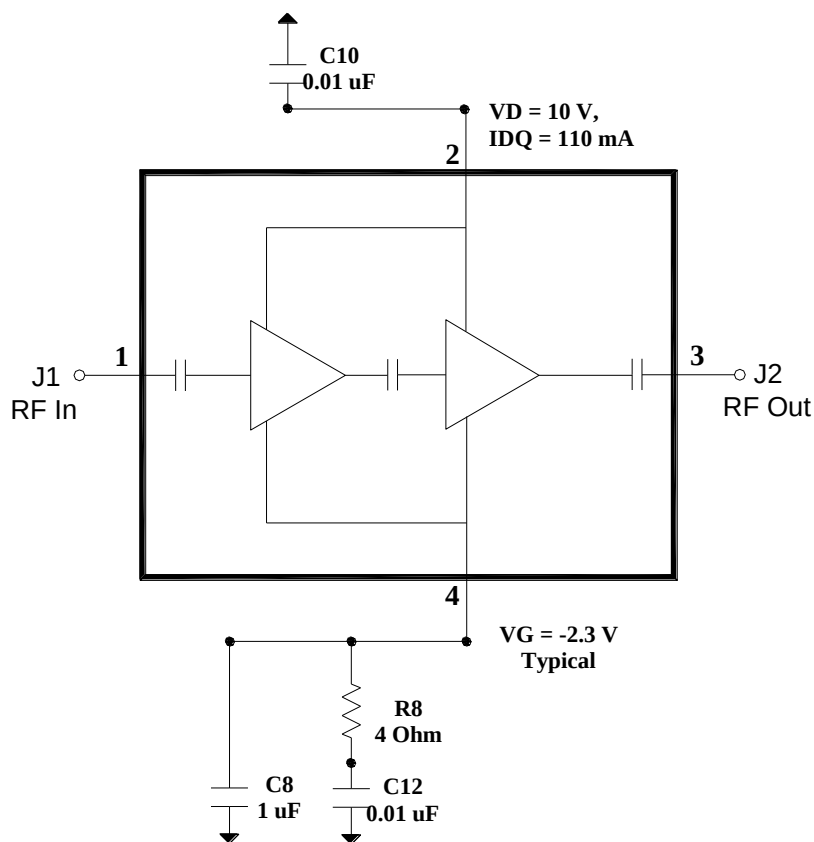


## Typical Performance

Conditions unless otherwise specified:  $V_D = 10V$ ,  $I_{DQ} = 110mA$ ,  $V_G = -2.3V$  Typical



## Application Circuit



### Bias-up Procedure

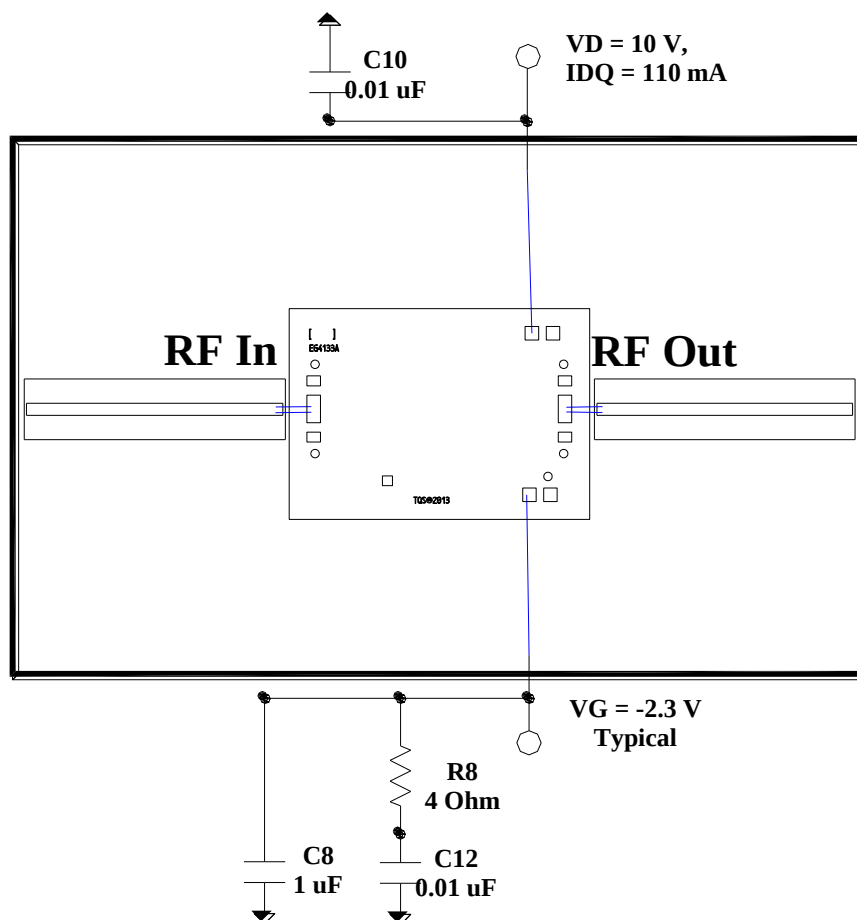
1. Set  $I_D$  limit to 175mA,  $I_G$  limit to 1mA
2. Apply -5V to  $V_G$  for pinch off
3. Apply +10V to  $V_D$
4. Adjust  $V_G$  more positive until  $I_{DQ} = 110\text{mA}$  ( $V_G \sim -2.3\text{ V Typical}$ )
5. Apply RF signal

### Bias-down Procedure

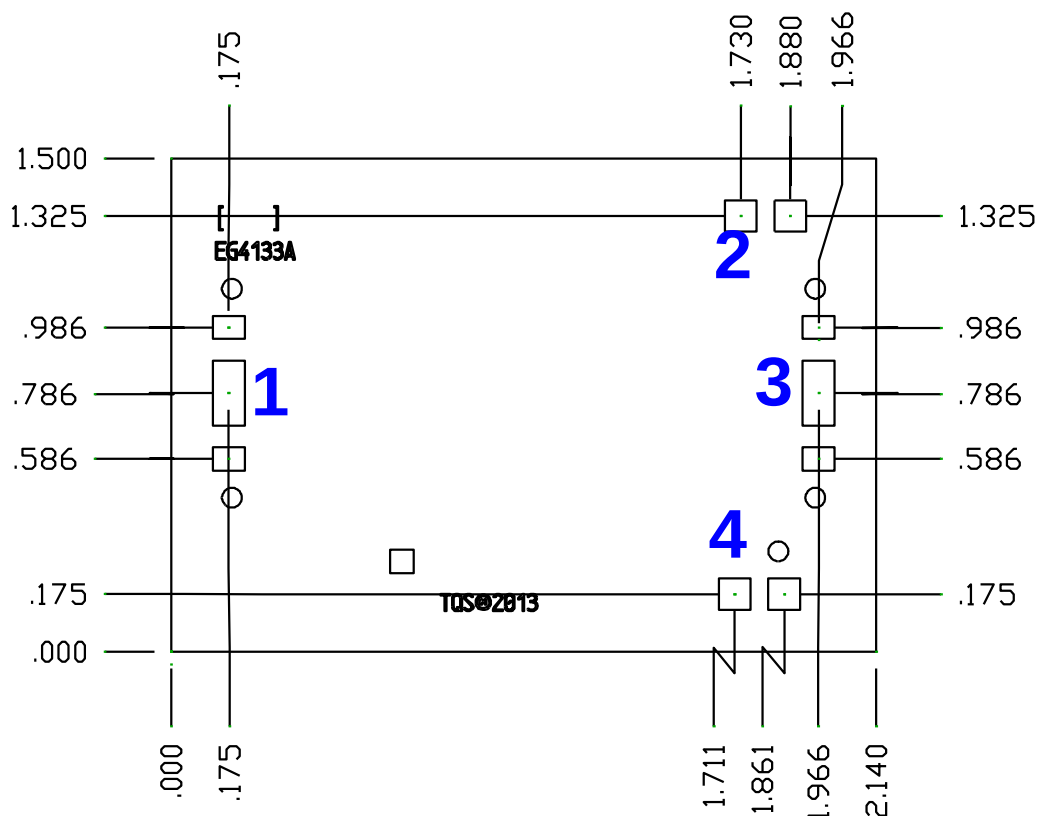
1. Turn off RF signal
2. Reduce  $V_G$  to -5V. Ensure  $I_{DQ} \sim 0\text{mA}$
3. Set  $V_D$  to 0V
4. Turn off  $V_D$  supply
5. Turn off  $V_G$  supply



**Assembly Drawing**



**Mechanical Drawing & Bond Pad Description**



Unit: millimeters  
Thickness: 0.10  
Die x, y size tolerance: +/- 0.050  
Chip edge to bond pad dimensions are shown to center of pad  
Ground is backside of die

| Bond Pad | Symbol         | Pad Size      | Description                                                                                                |
|----------|----------------|---------------|------------------------------------------------------------------------------------------------------------|
| 1        | RF In          | 0.096 x 0.196 | Input; matched to 50 ohms                                                                                  |
| 2        | V <sub>D</sub> | 0.096 x 0.096 | Drain voltage, V <sub>D</sub> . Bias network is required; see Application Circuit on page 8 as an example. |
| 3        | RF Out         | 0.096 x 0.196 | Output; matched to 50 ohms                                                                                 |
| 4        | V <sub>G</sub> | 0.096 x 0.096 | Gate voltage, V <sub>G</sub> . Bias network is required; see Application Circuit on page 8 as an example.  |

## Assembly Notes

Component placement and adhesive attachment assembly notes:

- Vacuum pencils and/or vacuum collets are the preferred method of pick up.
- Air bridges must be avoided during placement.
- The force impact is critical during auto placement.
- Organic attachment (i.e. epoxy) can be used in low-power applications.
- Curing should be done in a convection oven; proper exhaust is a safety concern.

Reflow process assembly notes:

- Use AuSn (80/20) solder and limit exposure to temperatures above 300°C to 3-4 minutes, maximum.
- An alloy station or conveyor furnace with reducing atmosphere should be used.
- Do not use any kind of flux.
- Coefficient of thermal expansion matching is critical for long-term reliability.
- Devices must be stored in a dry nitrogen atmosphere.

Interconnect process assembly notes:

- Thermosonic ball bonding is the preferred interconnect technique.
- Force, time, and ultrasonic are critical parameters.
- Aluminum wire should not be used.
- Devices with small pad sizes should be bonded with 0.0007-inch wire.

## Product Compliance Information

### ESD Sensitivity Ratings



Caution! ESD-Sensitive Device

ESD Rating: TBD  
Value: TBD  
Test: Human Body Model (HBM)  
Standard: JEDEC Standard JESD22-A114

### Solderability

This part is compliant with EU 2002/95/EC RoHS directive (Restrictions on the Use of Certain Hazardous Substances in Electrical and Electronic Equipment).

This product also has the following attributes:

- Lead Free
- Halogen Free (Chlorine, Bromine)
- Antimony Free
- TBBP-A (C<sub>15</sub>H<sub>12</sub>Br<sub>4</sub>O<sub>2</sub>) Free
- PFOS Free
- SVHC Free

### ECCN

US Department of Commerce: EAR99

## Contact Information

For the latest specifications, additional product information, worldwide sales and distribution locations, and information about TriQuint:

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Email: [info-sales@triquint.com](mailto:info-sales@triquint.com)

Tel: +1.972.994.8465  
Fax: +1.972.994.8504

For technical questions and application information: Email: [info-products@triquint.com](mailto:info-products@triquint.com)

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- Специальные условия для постоянных клиентов.
- Подбор аналогов.
- Поставку компонентов в любых объемах, удовлетворяющих вашим потребностям.
- Приемлемые сроки поставки, возможна ускоренная поставка.
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- Работу по проектам и поставку образцов.
- Формирование склада под заказчика.
- Сертификаты соответствия на поставляемую продукцию (по желанию клиента).
- Тестирование поставляемой продукции.
- Поставку компонентов, требующих военную и космическую приемку.
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- Техническую поддержку проекта.
- Защиту от снятия компонента с производства.
- Оценку стоимости проекта по компонентам.
- Изготовление тестовой платы монтаж и пусконаладочные работы.



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